

High- J_c YBa₂Cu₃O_{7- δ} superconducting film grown by laser-assisted chemical vapor deposition using a single liquid source and its microstructure

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Abstract: A YBa₂Cu₃O_{7- δ} (YBCO) film was prepared on a multilayer-coated Hastelloy C276 substrate by laser-assisted metalorganic chemical vapor deposition using a single liquid source precursor. A *c*-axis-oriented YBCO film was grown epitaxially on a (100) CeO₂ layer at the deposition rate of 11 $\mu\text{m h}^{-1}$. A screw dislocation and stacking faults were observed in the cross section of the YBCO film. The critical current density of the YBCO film reached 2.7 MA cm⁻².

Short title: High- J_c YBCO film grown by laser CVD using a single liquid source

74.62.Bf Effects of material synthesis, crystal structure, and chemical composition

68.55.-a Thin film structure and morphology

81.15.Gh Chemical vapor deposition (including plasma-enhanced CVD, MOCVD, etc.)

74.78.Bz High-T_c films

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Please cite this manuscript as:

P. Zhao, A. Ito, T. Kato, D. Yokoe, T. Hirayama, T. Goto: High- J_c YBa₂Cu₃O_{7- δ} superconducting film grown by laser-assisted chemical vapor deposition using a single liquid source and its microstructure, Superconductor Science and Technology 26 095016 (2013). doi:10.1088/0953-2048/26/9/095016

1. Introduction

Conductors coated with the high-temperature superconductor $\text{YBa}_2\text{Cu}_3\text{O}_{7-\delta}$ (YBCO) have been fabricated by various techniques, such as metal organic deposition using trifluoroacetates [1], pulsed laser deposition [2], and metalorganic chemical vapor deposition (MOCVD) [3,4]. Among these techniques, MOCVD is promising for the preparation of coated conductors because it not only provides a high deposition rate and uniform coverage but can also be adapted to a reel-to-reel deposition system for the fabrication of long-length wires.

A laser-assisted MOCVD (laser CVD) is advantageous for the preparation of oriented films at high deposition rates [5–7]. We prepared *c*-axis-oriented YBCO film on a multilayer-coated Hastelloy C276 tape at a high deposition rate of $55 \mu\text{m h}^{-1}$ [8]. This YBCO film exhibited a critical current density (J_c) of 0.5 MA cm^{-2} . For industrial applications, a high critical current density (J_c) greater than 1 MA cm^{-2} and high adaptability to a continuous production are required. In the previous study, Y, Ba, and Cu solid compounds were used as precursors, and the composition of the precursor vapor was independently controlled by varying the evaporation temperature of each precursor. However, a constant feed of multi-component vapor through the evaporation of solid precursors is difficult because of agglomeration and sintering, *i.e.*, changes in the surfaces of the precursors and the corresponding degradation of their surface state. However, the use of a liquid precursor to continuously and stably supply a precursor at a constant rate for a prolonged period is feasible.

Miyata *et al.* recently reported the high-rate preparation of YBCO superconducting films using laser CVD [9]. They also studied the mechanism of growth mode in laser CVD process taking into account of the relationship between deposition rate and precursor delivery rate, while the microstructure of high- J_c film prepared by laser CVD has not been elucidated.

In this study, we report the high-speed preparation of a high- J_c YBCO film exhibiting 2.7 MA cm^{-2} by laser CVD using a single liquid source precursor and its microstructure.

2. Experimental

$\text{Y}(\text{DPM})_3$, $\text{Ba}(\text{DPM})_2/\text{Ba}(\text{TMOD})_2$, and $\text{Cu}(\text{DPM})_2$ (DPM; dipivaloylmethanate and TMOD; 2,2,6,6-tetramethyl-3,5-octanedionate) precursors were dissolved in tetrahydrofuran ($\text{C}_4\text{H}_8\text{O}$; THF) at a Y concentration of 0.275 mol L^{-1} . The source solution was delivered into the evaporation chamber using a plunger pump at a supply rate of $0.83 \times 10^{-5} \text{ L s}^{-1}$. The evaporation chamber was heated to 653 K. The beam of a continuous-wave Nd:YAG laser (wavelength: $1064 \mu\text{m}$) was defocused up to 25 mm in diameter to irradiate the whole substrate was introduced into chamber through a quartz window [6]. A multilayer-coated Hastelloy C276 tape ($10 \times 5 \times 0.1 \text{ mm}$) with a structure of $\text{CeO}_2/\text{MgO}/\text{Y}_2\text{O}_3/\text{Al}_2\text{O}_3/\text{Hastelloy C276}$ was used as a substrate. The substrate was preheated at 823 K. The flow rates of Ar and O_2 gases were 1.52×10^{-6} and $0.34 \times 10^{-6} \text{ Pa m}^3 \text{ s}^{-1}$, respectively. The total pressure was maintained at 0.8 kPa. The deposition time was 180 s. The as-deposited YBCO films were heat treated in the sequence 573 K for 14.4 ks, 673 K

for 14.4 ks, and 773 K for 14.4 ks in a pure O₂ atmosphere (100 kPa) to transform the YBCO from its tetragonal to orthorhombic structure.

The phase was studied by X-ray diffraction (XRD; Rigaku RAD-2C). The out-of-plane crystallinity of the YBCO film was evaluated on the basis of the full-width at half-maximum (FWHM) of the ω -scan on the (005) reflection. The in-plane orientation was evaluated by the FWHM of the ϕ -scan on the (103) reflection, which was measured by a pole-figure X-ray diffractometer (XRD; Rigaku Ultima IV). The microstructure was observed using a field-emission scanning electron microscope (FESEM; JEOL JSM-7500F) and a transmission electron microscope (TEM; Topcon EM-002B). The composition was analyzed by an energy-dispersive X-ray spectrometer attached to the TEM (TEM-EDS). The schematic of the epitaxial relationship was illustrated using VESTA [10]. Ag electrodes of approximately 6- μm thickness were deposited onto the sample surface via dc sputtering and were connected to thin copper wires (dia. 0.1 mm). The critical current (I_c) was measured in liquid N₂ (77 K) using a dc four-probe method with the criterion of 1 $\mu\text{V cm}^{-1}$.

3. Results and discussion

Figure 1 shows the XRD pattern of the YBCO film prepared at a deposition temperature of 1020 K (laser power of 123 W). The YBCO film showed a *c*-axis orientation. The weak diffractions from the (100) and (200) planes suggested that a small amount of *a*-axis-oriented YBCO grains were present. A small amount of (110)-oriented BaCuO₂ (JCPDF #38-1402) was also observed. The FWHM of the ω -scan on the (005) reflection and that of the ϕ -scan on the (103) reflection of this YBCO film were 1.8° and 3.2°, respectively. These values imply that the orientation of this film was improved from that of YBCO films prepared using solid precursors in a previous study (2.0° and 3.8°, respectively) [8].

Figure 2 shows the X-ray pole figure pattern from the (103) reflection of the YBCO films and that from the (220) reflection of the CeO₂ layer. The pole figure of the (103) reflection of the YBCO film showed a fourfold pattern at approximately $\alpha = 44^\circ$, which was attributed to the YBCO {103} planes at a interior angle of 46° to the YBCO (001) plane. The pole figure of the (220) reflection of the CeO₂ film showed a fourfold pattern at approximately $\alpha = 45^\circ$, which corresponded to the CeO₂ {220} planes with an interior angle of 45° to the CeO₂ (100) plane. The azimuth angles β of the (103) reflections of the YBCO film were rotated 45° with respect to those of CeO₂ (220) reflections, which indicates the in-plane epitaxial growth relationship of YBCO [110] // CeO₂ [001].

Figure 3 shows the surface SEM images of the YBCO film and the schematic of the in-plane epitaxial relationship between the *c*-axis-oriented YBCO grains and the CeO₂ layer. The surface of the *c*-axis-oriented YBCO film was flat because of a coherent lattice matching between YBCO (001) and CeO₂ (100) planes (Fig. 3(b)). Needle-like grains (A in Fig. 3(a)) were distributed on the surface. *a*-axis-oriented YBCO grains were often found on the films as needle-like grains. Their longer directions, namely *c*-axis direction, were aligned orthogonally (Fig. 3(c)), which can be determined on the basis of X-ray pole figure and TEM

observation (Fig. 4). According to the calculation of the surface Gibbs energies of YBCO planes [11], *a*-axis orientation is much favored than *c*-axis orientation at lower deposition temperature and higher supersaturation. In addition, the increase in the amount of *a*-axis-oriented grains as the increase in the thickness of *c*-axis-oriented YBCO film has often been reported [12,13]. The *a*-axis-oriented YBCO grains were nucleated at grain boundary and surface roughness and grew larger in the *c*-axis-oriented YBCO films [14], resulted in the film surface consisting of needle-like grains and the decrease in the critical current density [12]. Outgrowth of flower-like grains were also observed (B and C in Fig. 3(a)), which were identified as Ba– and Cu–O compounds on the basis of the TEM-EDS analysis. TEM specimens of areas D were fabricated by a focused ion beam technique.

Figure 4 shows TEM images and selected-area electron diffraction (SAED) patterns of the *c*-axis oriented YBCO film. The cross-section of the YBCO film showed a dense structure with a thickness of 540 nm (Fig. 4(a), 4(b)), which indicates a deposition rate of $11 \mu\text{m h}^{-1}$. The SAED pattern from the CeO₂ layer suggested that the $\langle 100 \rangle$ direction of the CeO₂ film was normal to the substrate surface and that the $\langle 001 \rangle$ direction was parallel to the cross-section (Fig. 4(d)). The SAED pattern from the film cross section indicated that the $\langle 001 \rangle$ direction of the YBCO film was normal to the substrate surface and that the $\langle 110 \rangle$ direction was parallel to the cross-section (Fig. 4(e)). The in-plane epitaxial relationship between *c*-axis-oriented YBCO film and CeO₂ layer was confirmed to be YBCO $[110] // \text{CeO}_2 [001]$, which was the same result as the X-ray pole figure (Fig. 2). The needle-like grain, namely *a*-axis oriented YBCO grains were grown on the film surface (grain A in Fig. 4(b)). From the SAED pattern of *a*-axis-oriented YBCO grain (Fig. 4(f)), the in-plane epitaxial relationship among *a*-axis-oriented YBCO grain, *c*-axis oriented YBCO film and CeO₂ layer was confirmed to be *a*-YBCO $[011] // c$ -YBCO $[110] // \text{CeO}_2 [001]$, which was the same results as the X-ray pole figure and SEM observation (Figs. 2 and 3). The flower-like outgrowth grain was grown on the surface of *c*-axis oriented YBCO film (grain C in Fig. 4(a)), while the other grain was partially embedded in the film (grain B in Fig. 4(b)). Screw dislocations and stacking faults were identified in the dark-field cross-sectional image of the YBCO film (Fig. 4(c)). The dark-field images were taken under the $\mathbf{g} = 006$ of YBCO condition. In this condition, dislocations having the Burgers components of the 100 or 110 directions are disappeared. Therefore, screw dislocations can be visualized because these Burgers components have the 001 direction of YBCO.

Figure 5 shows the *I–V* curve for the *c*-axis-oriented YBCO film. As the current was increased, the voltage initially remained zero and started to increase when the current reached to 60 A, which indicates a high J_c of 2.7 MA cm^{-2} . The J_c value obtained in the present study was greater than those of YBCO films ($0.5\text{--}2.6 \text{ MA cm}^{-2}$) prepared on multilayer-coated Hastelloy C276 tape by MOCVD [16,17] and laser-assisted CVD [8,9]

A current flow in type II superconductors such as YBCO causes a transition into a mixed state. A magnetic vortex in the superconductor moves by Lorentz force, resulting in the decline in the critical current. However, non-superconducting phases distributed in the type II superconductor act as a flux pinning to

sustain high current capability [15]. Several pinning centers have been proposed: zero-dimensional point defects, one-dimensional linear defects such as screw and edge dislocations, two-dimensional planar defects such as grain boundaries and twin planes, three-dimensional defects such as secondary phase precipitations. Among them, one-dimensional pinning centers exhibit a strong pinning force against a flux line parallel to the pinning center. Because the superconducting current passes on *ab* plane of *c*-axis-oriented YBCO films, the screw dislocations perpendicular to the film might play a role of pinning center and be responsible for the enhancement of J_c in the YBCO film.

4. Conclusions

By using laser CVD with a single liquid source precursor, we prepared a *c*-axis-oriented YBCO film that exhibited a high J_c of 2.7 MA cm^{-2} on multilayer-coated Hastelloy C276. The in-plane epitaxial relationship was YBCO [110] // CeO₂ [001]. A screw dislocation and stacking fault defects were observed in the dark-field cross-sectional image of the *c*-axis-oriented YBCO film.

Acknowledgements

This work was supported in part by the International Superconductivity Technology Center (ISTEC). This work was also supported in part by JSPS, Grant-in-Aid for Young Scientists (A), No. 25709069, and by the 111 Project, China (B13035).

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Figure captions

Fig. 1 XRD pattern of the YBCO film prepared on multilayer-coated Hastelloy C273 substrate at deposition temperature of 1020 K.

Fig. 2 X-ray pole figure of the YBCO and CeO₂ layers for the YBCO film prepared on multilayer-coated Hastelloy C273 substrate at deposition temperature of 1020 K.

Fig. 3 Surface SEM images of the *c*-axis-oriented YBCO film (a). Images (b) and (c) illustrate in-plane epitaxial relationship between the *c*- and *a*-axis-oriented YBCO grains and (100) CeO₂ plane, respectively.

Fig. 4 TEM bright-field images (a, b), dark-field image (c) and SAED patterns (d–f) of the *c*-axis-oriented YBCO film prepared on multilayer-coated Hastelloy C273 substrate at deposition temperature of 1020 K.

Fig. 5 *I–V* curve of the *c*-axis-oriented YBCO film prepared on multilayer-coated Hastelloy C273 substrate at deposition temperature of 1020 K.

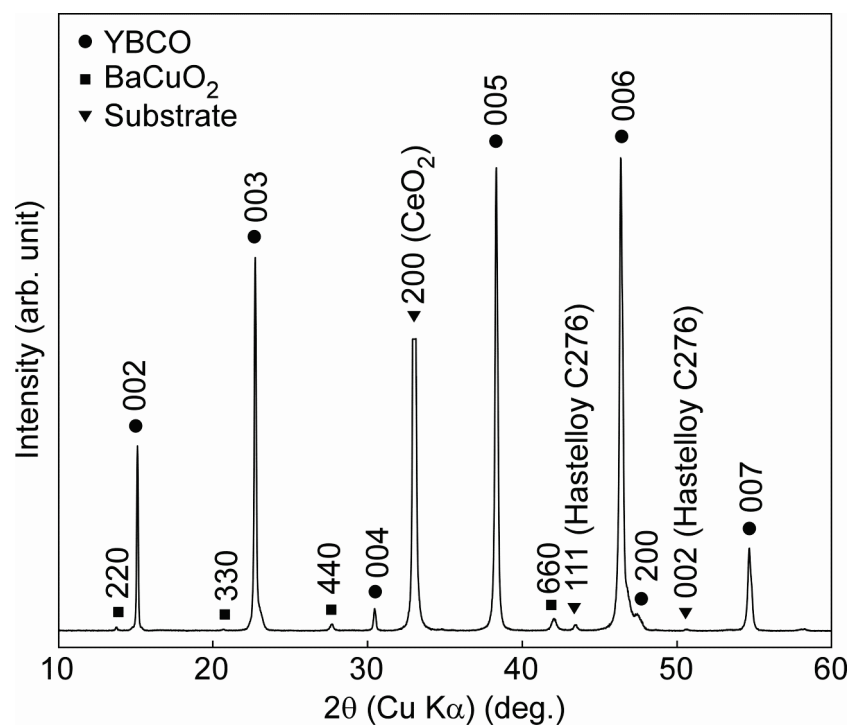


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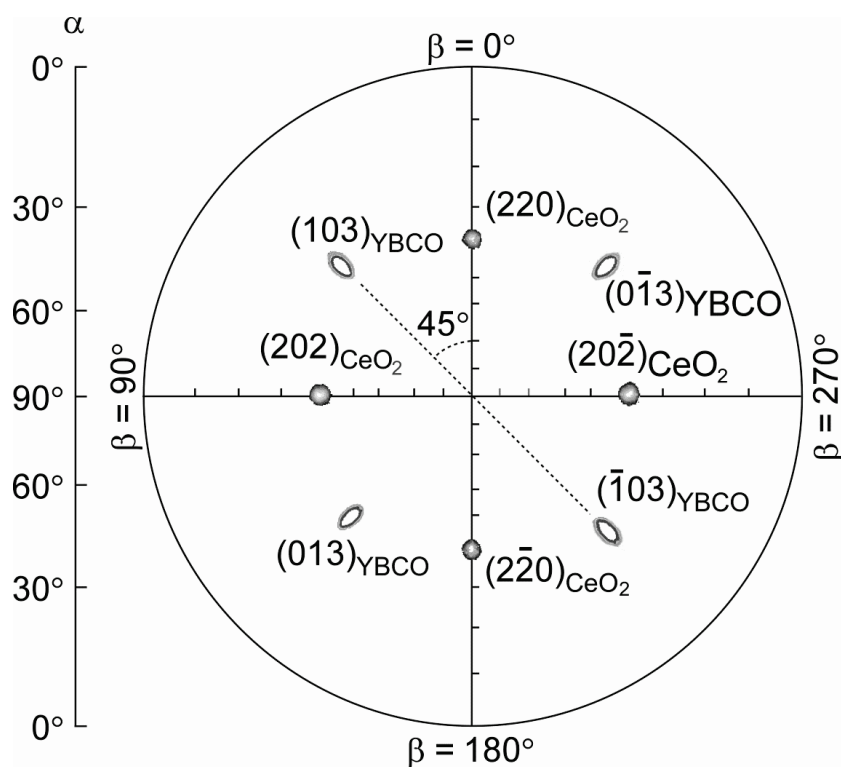


Fig. 2 X-ray pole figure of the YBCO and CeO₂ layers for the YBCO film prepared on multilayer-coated Hastelloy C273 substrate at deposition temperature of 1020 K.

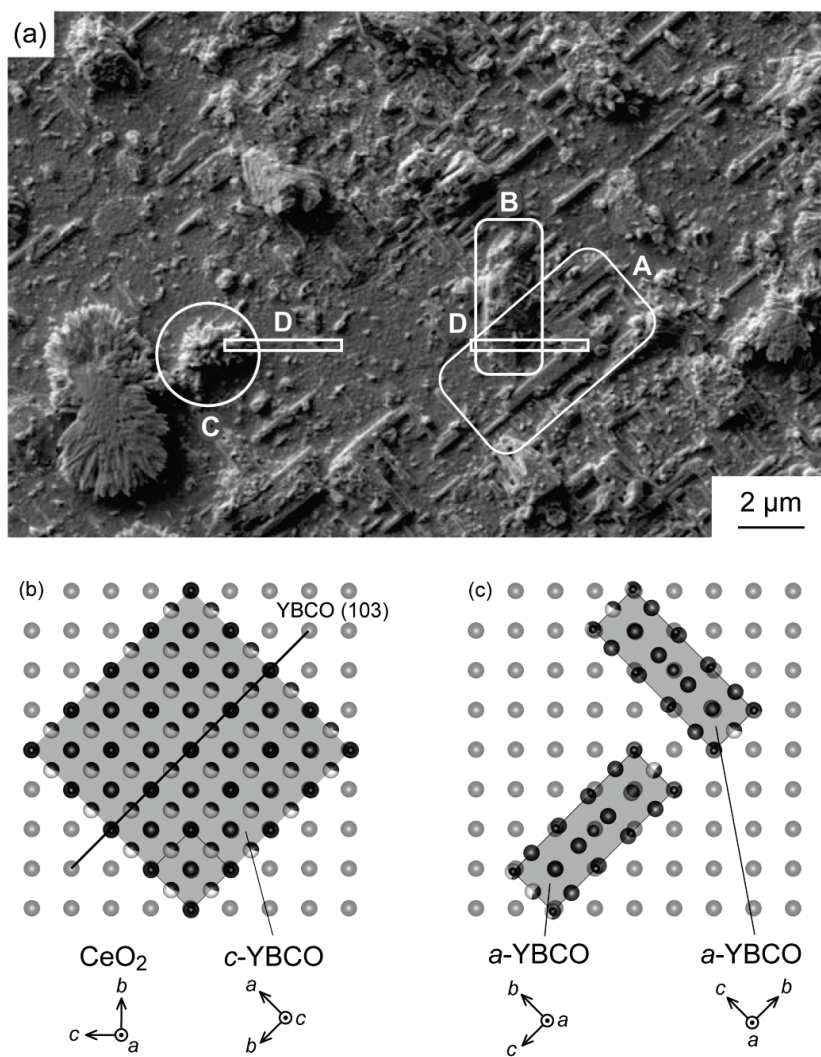


Fig. 3 Surface SEM images of the *c*-axis-oriented YBCO film (a). Images (b) and (c) illustrate in-plane epitaxial relationship between the *c*- and *a*-axis-oriented YBCO grains and (100) CeO₂ plane, respectively.

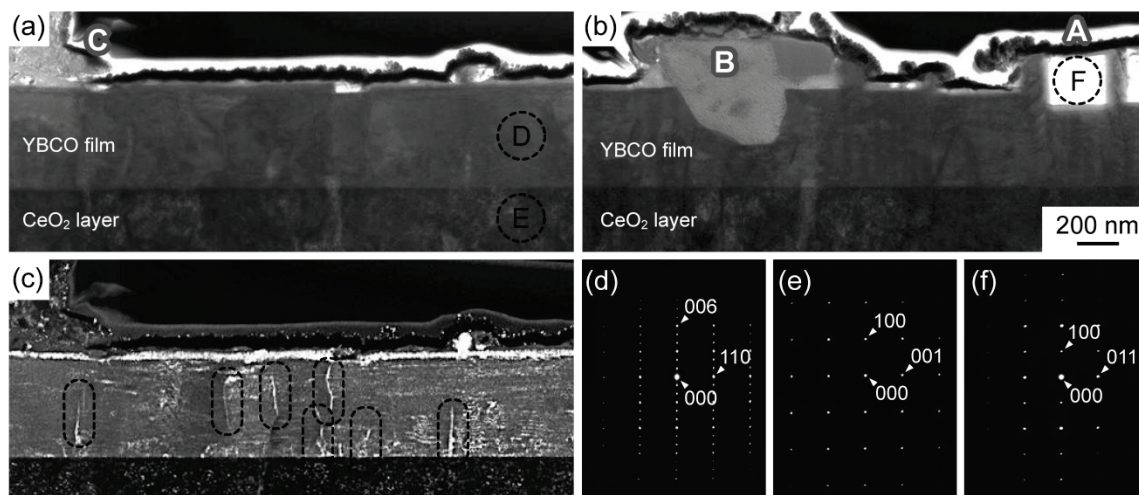


Fig. 4 TEM bright-field images (a, b), dark-field image (c) of the *c*-axis-oriented YBCO film prepared on multilayer-coated Hastelloy C273 substrate at deposition temperature of 1020 K. SAED patterns (d-f) were taken from circles D-F, respectively.

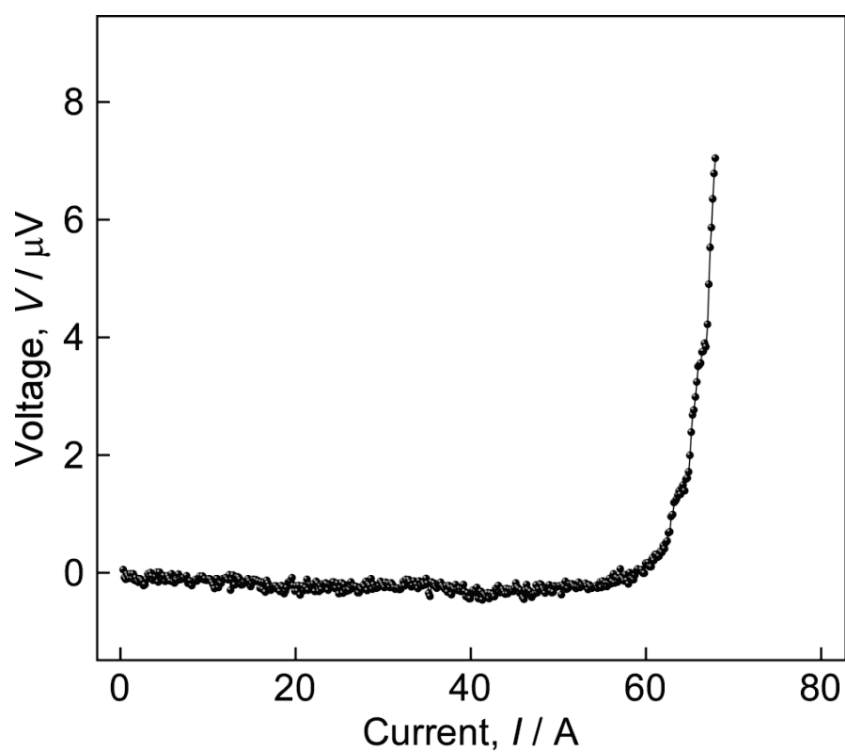


Fig. 5 I - V curve of the c -axis-oriented YBCO film prepared on multilayer-coated Hastelloy C273 substrate at deposition temperature of 1020 K.